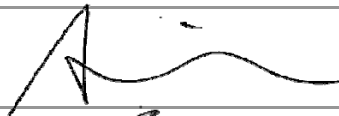



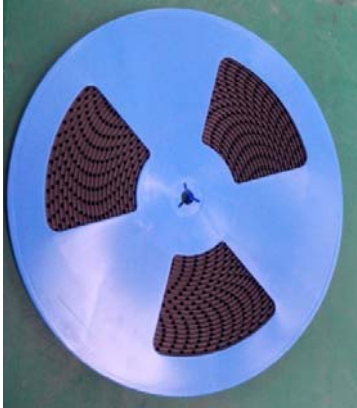


Product/Process Change Notification

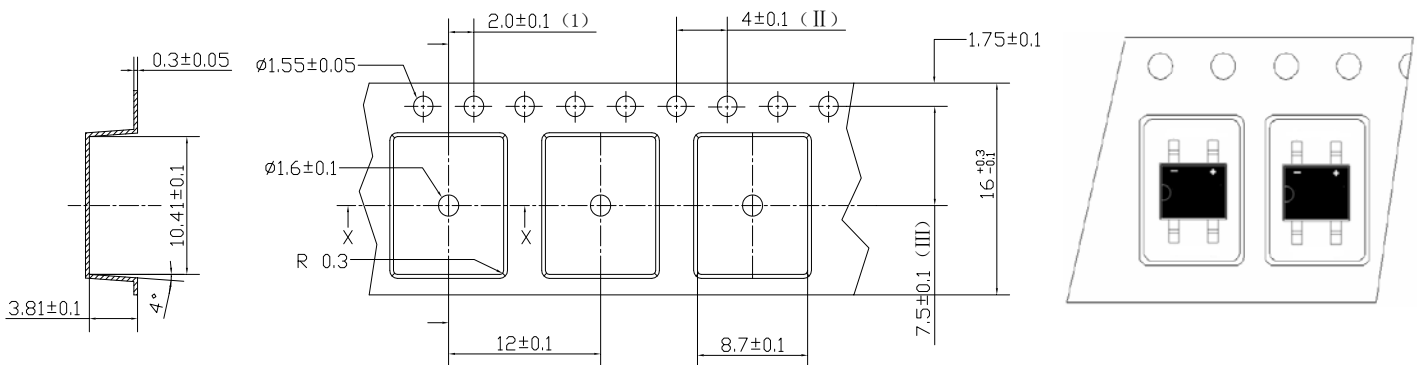
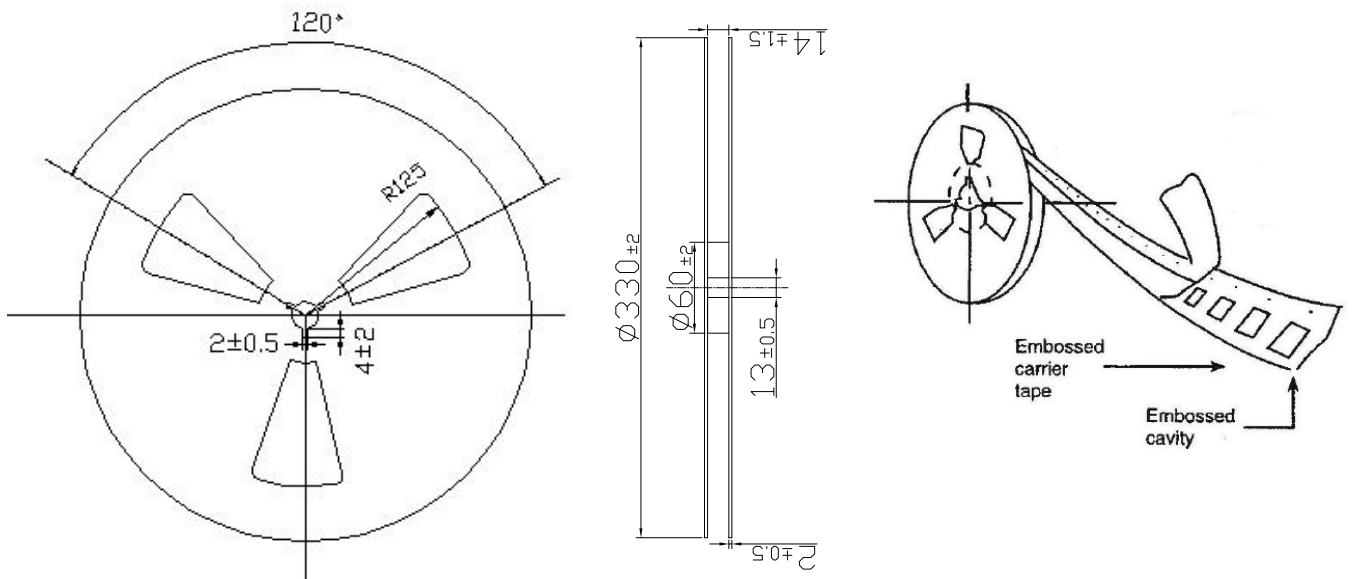
PCN#	Effective Date	Issue Date
2014-08-22C-01	2014/11/22	2014/8/22
PCN Classification	Product Category	
Major	Bridge Diode	
Subject		
Change assembly factory for DB-1S package		
Affected Product(s)		
DB1501S~DB1507S. DB201S~DB207S.		
Description of Change(s)		
Original assembly factory EOL, thus we change assembly factory; The new assembly factory Good-ARK electronics CO., LTD, located in the No.31 Tongxi Road, TongAn Economic Development Zone, 215153, Suzhou, Jiangsu, P.R.China.		
Content of Change(s)		
Assembly house.		
Impact(s)		
None		
Attachment(s)		
Reliability test report. SGS Report. Packge information. Specification.		

Approval		
Issue by	Alice Lai	e-mail: alice@secosgmbh.com
Development Engineer		Alice Lai
QA Manager		Peter Yang
General Manger		Mathew Liu

For more information, please contact us directly or visit our website <http://www.secosgmbh.com>

Reference of	
Original	News
 <p>Top View</p>	 <p>Top View</p>
 <p>Back View</p>	 <p>Back View</p>
 <p>Reel</p>	 <p>Reel</p>

DB-1S



Unit: mm

Reel	Reel Size	Box	Box Size (mm)	Carton	Carton Size (mm)
1,500pcs	13 inch	3,000 pcs	350*350*40	24,000	350*350*350



SeCoS Corporation

Reliability Testing Summary Report

Date: 2014/08/20

Document No.: SH14 -08- 01

Test Item	P/N	Test Condition	(LTPD)	Sample Numbers	Allow Fall Numbers	Fall Numbers	Result
HTRB High Temp Reverse Bias	DB1507S	100 ± 10°C, 80% VR, T = 1000hrs		77	0	0	ACC
HTSL High Temperature Storage Life	DB1507S	150°C, T = 1000 hrs		77	0	0	ACC
PCT Pressure Cooker Test	DB1507S	121°C, 29.7PSIG, 168 hrs		77	0	0	ACC
TCT Temperature Cycle Test	DB1507S	-55°C/30min, 150°C/30min, For 1000 Cycle		77	0	0	ACC
THT High Temperature High Humidity Test	DB1507S	85 ± 2°C, RH=85±5%, 1000 hrs		77	0	0	ACC
Solderability	DB1507S	245 ± 5°C / 5Sec, The inspected area of each lead must have 95% solder coverage minimum.		10	0	0	ACC

Judgment:

qualified unqualified

Testing Start Date: 2014.07.01 Testing End Date: 2014.08.20

Tester: Leo Hsia Approval: Peter Yang



SeCoS Corporation

Electrical Test Data

Report No : T140820-001

Part No : DB1507S

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<1100mV@IF=1.5A, IR<10uA@VR=1000V

Test Condition: 25°C

Test Date: 2014.07.01 ~ 2014.07.01

Test Standard : Specifications

Operator: Leo Hsia

Test Result: PASS

No	VF (mV)	IR (uA)
1	938.0mV	0.098uA
2	935.0mV	0.032uA
3	941.1mV	0.085uA
4	942.1mV	0.043uA
5	935.3mV	0.088uA
6	943.3mV	0.094uA
7	937.4mV	0.093uA
8	938.4mV	0.042uA
9	939.9mV	0.041uA
10	937.2mV	0.069uA
11	940.3mV	0.096uA
12	934.2mV	0.033uA
13	938.6mV	0.072uA
14	942.1mV	0.037uA
15	935.3mV	0.043uA
16	938.5mV	0.057uA
17	940.6mV	0.072uA
18	936.8mV	0.044uA
19	941.6mV	0.088uA
20	938.9mV	0.059uA
21	939.9mV	0.054uA
22	940.2mV	0.035uA
23	943.5mV	0.084uA
24	942.0mV	0.054uA
25	936.2mV	0.069uA
26	935.8mV	0.038uA
27	941.0mV	0.045uA
28	941.4mV	0.041uA
29	938.0mV	0.042uA
30	943.0mV	0.050uA
31	941.2mV	0.041uA
32	943.1mV	0.079uA
33	943.0mV	0.086uA
34	941.4mV	0.092uA
35	940.7mV	0.073uA
36	939.7mV	0.050uA
37	938.8mV	0.081uA
38	941.9mV	0.058uA
39	939.5mV	0.096uA
40	943.8mV	0.077uA
41	943.1mV	0.044uA



SeCoS Corporation

Electrical Test Data

Report No : T140820-001

Part No : DB1507S

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<1100mV@IF=1.5A, IR<10uA@VR=1000V

Test Condition: 25°C

Test Date: 2014.07.01 ~ 2014.07.01

Test Standard : Specifications

Operator: Leo Hsia

Test Result: PASS

No	VF (mV)	IR (uA)
42	939.0mV	0.032uA
43	940.7mV	0.032uA
44	939.4mV	0.091uA
45	937.2mV	0.046uA
46	944.0mV	0.086uA
47	937.5mV	0.047uA
48	937.8mV	0.091uA
49	935.9mV	0.056uA
50	941.6mV	0.063uA
51	934.5mV	0.065uA
52	935.2mV	0.031uA
53	934.3mV	0.035uA
54	940.6mV	0.033uA
55	940.8mV	0.068uA
56	940.4mV	0.080uA
57	941.1mV	0.046uA
58	943.0mV	0.093uA
59	934.8mV	0.049uA
60	936.8mV	0.044uA
61	940.9mV	0.043uA
62	938.9mV	0.088uA
63	940.6mV	0.082uA
64	940.1mV	0.087uA
65	939.9mV	0.052uA
66	934.8mV	0.034uA
67	938.2mV	0.095uA
68	936.4mV	0.046uA
69	938.9mV	0.039uA
70	943.4mV	0.082uA
71	936.5mV	0.046uA
72	937.5mV	0.069uA
73	936.4mV	0.091uA
74	943.0mV	0.073uA
75	943.6mV	0.044uA
76	938.7mV	0.049uA
77	941.5mV	0.037uA

Made By: Leo Hsia

Approval: Peter Yang



High Temperature Reverse Bias Test Data

Report No : T140820-001

Part No : DB1507S

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<1100mV@IF=1.5A, IR<10uA@VR=1000V

Test Condition: 100 ± 10°C, 80% VR, T = 1000 hrs

Test Date: 2014.07.01 ~ 2014.08.13

Test Standard : JESD22 STANDER Method-A108

Operator: Leo Hsia

Test Result: PASS

No	Before		After	
	VF (mV)	IR (uA)	VF (mV)	IR (uA)
1	936.7mV	0.092uA	941.2mV	0.082uA
2	942.0mV	0.066uA	935.0mV	0.047uA
3	941.0mV	0.052uA	941.9mV	0.076uA
4	941.1mV	0.040uA	942.3mV	0.036uA
5	941.0mV	0.098uA	936.0mV	0.072uA
6	937.5mV	0.071uA	936.4mV	0.090uA
7	936.7mV	0.081uA	942.2mV	0.055uA
8	937.3mV	0.038uA	941.7mV	0.049uA
9	936.9mV	0.075uA	940.7mV	0.043uA
10	935.9mV	0.048uA	939.2mV	0.079uA
11	935.0mV	0.098uA	939.6mV	0.096uA
12	939.6mV	0.095uA	938.5mV	0.090uA
13	943.1mV	0.066uA	943.6mV	0.097uA
14	940.8mV	0.071uA	939.6mV	0.062uA
15	937.5mV	0.042uA	942.0mV	0.030uA
16	936.5mV	0.035uA	943.0mV	0.050uA
17	940.2mV	0.047uA	938.2mV	0.048uA
18	935.6mV	0.052uA	943.9mV	0.045uA
19	937.7mV	0.091uA	935.6mV	0.069uA
20	941.8mV	0.094uA	936.7mV	0.061uA
21	940.7mV	0.084uA	937.5mV	0.062uA
22	937.5mV	0.075uA	944.1mV	0.070uA
23	943.0mV	0.038uA	944.1mV	0.094uA
24	941.2mV	0.080uA	939.4mV	0.055uA
25	934.8mV	0.093uA	938.2mV	0.076uA
26	937.5mV	0.092uA	939.5mV	0.083uA
27	936.6mV	0.070uA	935.4mV	0.035uA
28	938.2mV	0.068uA	934.9mV	0.091uA
29	936.7mV	0.094uA	937.6mV	0.043uA
30	943.4mV	0.066uA	934.9mV	0.078uA
31	943.5mV	0.081uA	935.1mV	0.042uA
32	937.7mV	0.078uA	937.2mV	0.080uA
33	943.8mV	0.088uA	941.2mV	0.077uA
34	937.8mV	0.082uA	934.6mV	0.085uA
35	939.3mV	0.061uA	937.7mV	0.080uA
36	935.3mV	0.079uA	938.7mV	0.082uA
37	939.8mV	0.066uA	941.9mV	0.058uA
38	943.4mV	0.092uA	941.6mV	0.086uA
39	935.2mV	0.059uA	941.2mV	0.060uA
40	941.9mV	0.054uA	942.0mV	0.075uA



High Temperature Reverse Bias Test Data

Report No : T140820-001

Part No : DB1507S

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<1100mV@IF=1.5A, IR<10uA@VR=1000V

Test Condition: 100 ± 10°C, 80% VR, T = 1000 hrs

Test Date: 2014.07.01 ~ 2014.08.13

Test Standard : JESD22 STANDER Method-A108

Operator: Leo Hsia

Test Result: PASS

No	Before		After	
	VF (mV)	IR (uA)	VF (mV)	IR (uA)
41	936.4mV	0.044uA	937.4mV	0.093uA
42	938.5mV	0.098uA	939.1mV	0.048uA
43	935.7mV	0.030uA	943.2mV	0.047uA
44	943.7mV	0.088uA	943.8mV	0.072uA
45	936.8mV	0.042uA	938.6mV	0.073uA
46	942.9mV	0.050uA	939.4mV	0.070uA
47	939.3mV	0.099uA	935.0mV	0.090uA
48	936.6mV	0.079uA	939.9mV	0.038uA
49	938.3mV	0.097uA	942.8mV	0.049uA
50	936.9mV	0.040uA	934.2mV	0.098uA
51	943.3mV	0.077uA	938.3mV	0.040uA
52	943.1mV	0.043uA	937.0mV	0.051uA
53	942.2mV	0.077uA	941.8mV	0.077uA
54	939.5mV	0.035uA	942.1mV	0.069uA
55	943.1mV	0.034uA	937.1mV	0.080uA
56	936.6mV	0.093uA	939.6mV	0.062uA
57	935.4mV	0.092uA	943.8mV	0.078uA
58	937.9mV	0.088uA	942.1mV	0.042uA
59	940.0mV	0.030uA	942.2mV	0.059uA
60	941.0mV	0.094uA	942.5mV	0.079uA
61	941.0mV	0.040uA	942.6mV	0.073uA
62	941.6mV	0.050uA	934.9mV	0.054uA
63	942.2mV	0.071uA	943.4mV	0.070uA
64	936.4mV	0.090uA	935.1mV	0.080uA
65	941.9mV	0.039uA	943.6mV	0.074uA
66	935.2mV	0.082uA	937.8mV	0.072uA
67	942.1mV	0.070uA	934.9mV	0.092uA
68	943.8mV	0.060uA	942.4mV	0.046uA
69	941.6mV	0.039uA	942.7mV	0.096uA
70	935.2mV	0.038uA	944.0mV	0.077uA
71	935.1mV	0.064uA	939.1mV	0.087uA
72	940.8mV	0.049uA	943.4mV	0.043uA
73	937.8mV	0.048uA	937.1mV	0.058uA
74	940.9mV	0.096uA	939.8mV	0.045uA
75	935.5mV	0.070uA	940.5mV	0.062uA
76	938.3mV	0.036uA	942.2mV	0.069uA
77	937.4mV	0.099uA	934.5mV	0.085uA



High Temperature Storage Life Test Data

Report No : T140820-001

Part No : DB1507S

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<1100mV@IF=1.5A, IR<10uA@VR=1000V

Test Condition: 150°C, 1000Hrs

Test Date: 2014.07.01 ~ 2014.08.13

Test Standard : JESD22 STANDER Method-A103

Operator: Leo Hsia

Test Result: PASS

No	Before		After	
	VF (mV)	IR (uA)	VF (mV)	IR (uA)
1	934.9mV	0.041uA	941.4mV	0.043uA
2	942.4mV	0.096uA	941.7mV	0.055uA
3	942.4mV	0.071uA	943.3mV	0.045uA
4	936.4mV	0.095uA	941.9mV	0.096uA
5	941.0mV	0.094uA	938.9mV	0.057uA
6	937.0mV	0.082uA	936.1mV	0.073uA
7	942.1mV	0.080uA	943.7mV	0.061uA
8	944.1mV	0.037uA	939.3mV	0.063uA
9	937.3mV	0.095uA	939.5mV	0.089uA
10	939.6mV	0.038uA	940.5mV	0.094uA
11	942.8mV	0.092uA	938.5mV	0.043uA
12	936.2mV	0.066uA	943.6mV	0.077uA
13	936.8mV	0.068uA	940.5mV	0.091uA
14	943.9mV	0.061uA	938.8mV	0.082uA
15	938.8mV	0.053uA	941.3mV	0.061uA
16	942.8mV	0.066uA	939.4mV	0.080uA
17	940.1mV	0.056uA	935.8mV	0.077uA
18	940.4mV	0.074uA	943.5mV	0.085uA
19	934.3mV	0.075uA	940.2mV	0.038uA
20	936.2mV	0.094uA	938.8mV	0.057uA
21	935.0mV	0.067uA	937.0mV	0.078uA
22	942.8mV	0.096uA	940.5mV	0.040uA
23	939.2mV	0.052uA	944.0mV	0.061uA
24	935.9mV	0.085uA	936.2mV	0.065uA
25	937.1mV	0.054uA	941.5mV	0.081uA
26	942.4mV	0.034uA	937.6mV	0.072uA
27	936.5mV	0.059uA	939.1mV	0.043uA
28	937.4mV	0.094uA	940.5mV	0.038uA
29	943.8mV	0.041uA	938.8mV	0.077uA
30	943.3mV	0.096uA	942.4mV	0.074uA
31	941.5mV	0.076uA	938.7mV	0.061uA
32	939.7mV	0.044uA	939.9mV	0.075uA
33	934.3mV	0.041uA	936.5mV	0.052uA
34	941.7mV	0.044uA	936.8mV	0.041uA
35	936.3mV	0.043uA	943.8mV	0.031uA
36	938.7mV	0.069uA	936.2mV	0.057uA
37	938.0mV	0.049uA	941.0mV	0.034uA
38	935.4mV	0.093uA	940.7mV	0.095uA
39	935.4mV	0.086uA	942.2mV	0.047uA
40	937.3mV	0.093uA	939.9mV	0.096uA



High Temperature Storage Life Test Data

Report No : T140820-001

Part No : DB1507S

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<1100mV@IF=1.5A, IR<10uA@VR=1000V

Test Condition: 150°C, 1000Hrs

Test Date: 2014.07.01 ~ 2014.08.13

Test Standard : JESD22 STANDER Method-A103

Operator: Leo Hsia

Test Result: PASS

No	Before		After	
	VF (mV)	IR (uA)	VF (mV)	IR (uA)
41	942.7mV	0.054uA	935.4mV	0.031uA
42	943.2mV	0.069uA	941.5mV	0.045uA
43	935.4mV	0.090uA	942.6mV	0.068uA
44	940.7mV	0.056uA	944.1mV	0.057uA
45	943.4mV	0.030uA	943.0mV	0.062uA
46	936.7mV	0.058uA	936.8mV	0.098uA
47	936.8mV	0.033uA	938.0mV	0.045uA
48	938.6mV	0.062uA	937.9mV	0.095uA
49	939.5mV	0.045uA	941.0mV	0.045uA
50	942.5mV	0.055uA	939.9mV	0.036uA
51	938.4mV	0.081uA	936.2mV	0.056uA
52	942.5mV	0.073uA	942.4mV	0.035uA
53	943.2mV	0.044uA	940.9mV	0.081uA
54	940.5mV	0.053uA	936.1mV	0.067uA
55	936.1mV	0.088uA	936.5mV	0.090uA
56	935.2mV	0.042uA	935.8mV	0.064uA
57	944.0mV	0.077uA	934.3mV	0.069uA
58	942.3mV	0.068uA	939.4mV	0.082uA
59	940.7mV	0.037uA	938.1mV	0.076uA
60	943.9mV	0.090uA	940.4mV	0.069uA
61	943.1mV	0.037uA	937.9mV	0.064uA
62	941.6mV	0.086uA	937.4mV	0.055uA
63	936.4mV	0.085uA	936.5mV	0.096uA
64	936.0mV	0.090uA	943.8mV	0.087uA
65	943.7mV	0.034uA	939.8mV	0.099uA
66	935.1mV	0.098uA	942.4mV	0.040uA
67	939.5mV	0.081uA	939.3mV	0.078uA
68	939.3mV	0.031uA	943.0mV	0.053uA
69	936.3mV	0.091uA	942.1mV	0.097uA
70	940.3mV	0.090uA	937.8mV	0.081uA
71	941.3mV	0.075uA	943.2mV	0.057uA
72	943.4mV	0.085uA	940.1mV	0.090uA
73	940.7mV	0.032uA	938.3mV	0.048uA
74	942.4mV	0.088uA	942.3mV	0.061uA
75	943.4mV	0.047uA	934.2mV	0.090uA
76	937.3mV	0.038uA	938.9mV	0.042uA
77	942.5mV	0.086uA	942.2mV	0.032uA



SeCoS Corporation

Pressure Cooker Test Data

Report No : T140820-001

Part No : DB1507S

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<1100mV@IF=1.5A, IR<10uA@VR=1000V

Test Condition: 121°C, 100%RH, 29.7PSIG, 168Hrs

Test Date: 2014.07.07 ~ 2014.07.15

Test Standard : JESD22 STANDER Method-A102

Operator: Leo Hsia

Test Result: PASS

No	Before		After	
	VF (mV)	IR (uA)	VF (mV)	IR (uA)
1	941.0mV	0.070uA	943.9mV	0.066uA
2	940.8mV	0.086uA	935.6mV	0.089uA
3	934.6mV	0.043uA	935.7mV	0.093uA
4	943.9mV	0.092uA	938.2mV	0.080uA
5	941.4mV	0.097uA	941.9mV	0.042uA
6	936.9mV	0.062uA	939.0mV	0.044uA
7	943.2mV	0.063uA	940.5mV	0.083uA
8	941.1mV	0.052uA	944.1mV	0.068uA
9	939.5mV	0.061uA	942.5mV	0.051uA
10	936.1mV	0.059uA	938.2mV	0.085uA
11	940.0mV	0.060uA	938.2mV	0.082uA
12	937.0mV	0.065uA	938.5mV	0.058uA
13	935.9mV	0.058uA	942.9mV	0.061uA
14	941.9mV	0.097uA	943.2mV	0.037uA
15	943.8mV	0.081uA	942.3mV	0.042uA
16	937.9mV	0.089uA	943.2mV	0.059uA
17	936.6mV	0.041uA	942.2mV	0.094uA
18	939.9mV	0.093uA	935.1mV	0.079uA
19	937.3mV	0.098uA	939.8mV	0.082uA
20	935.8mV	0.080uA	938.7mV	0.042uA
21	941.5mV	0.054uA	942.0mV	0.032uA
22	939.6mV	0.080uA	937.9mV	0.036uA
23	941.7mV	0.068uA	935.4mV	0.092uA
24	935.4mV	0.083uA	935.6mV	0.076uA
25	936.2mV	0.084uA	935.9mV	0.087uA
26	942.7mV	0.036uA	941.2mV	0.082uA
27	940.7mV	0.054uA	938.6mV	0.065uA
28	939.1mV	0.086uA	940.9mV	0.082uA
29	935.3mV	0.053uA	934.7mV	0.040uA
30	937.2mV	0.043uA	936.4mV	0.052uA
31	942.9mV	0.082uA	936.4mV	0.060uA
32	940.8mV	0.064uA	944.0mV	0.091uA
33	935.2mV	0.076uA	939.9mV	0.068uA
34	943.6mV	0.090uA	934.7mV	0.065uA
35	940.1mV	0.084uA	936.8mV	0.093uA
36	940.9mV	0.090uA	934.6mV	0.059uA
37	934.8mV	0.036uA	936.9mV	0.092uA
38	938.2mV	0.084uA	941.7mV	0.030uA
39	937.1mV	0.078uA	936.9mV	0.056uA
40	936.9mV	0.051uA	937.7mV	0.071uA



SeCoS Corporation

Pressure Cooker Test Data

Report No : T140820-001

Part No : DB1507S

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<1100mV@IF=1.5A, IR<10uA@VR=1000V

Test Condition: 121°C, 100%RH, 29.7PSIG, 168Hrs

Test Date: 2014.07.07 ~ 2014.07.15

Test Standard : JESD22 STANDER Method-A102

Operator: Leo Hsia

Test Result: PASS

No	Before		After	
	VF (mV)	IR (uA)	VF (mV)	IR (uA)
41	936.9mV	0.093uA	941.4mV	0.060uA
42	937.1mV	0.064uA	939.9mV	0.055uA
43	936.6mV	0.040uA	940.6mV	0.058uA
44	936.7mV	0.039uA	936.7mV	0.080uA
45	937.4mV	0.074uA	938.0mV	0.084uA
46	941.9mV	0.067uA	940.8mV	0.071uA
47	934.4mV	0.097uA	934.9mV	0.092uA
48	943.1mV	0.085uA	938.9mV	0.081uA
49	943.7mV	0.053uA	942.1mV	0.070uA
50	944.0mV	0.041uA	936.1mV	0.075uA
51	936.2mV	0.072uA	943.8mV	0.039uA
52	934.6mV	0.033uA	942.1mV	0.076uA
53	939.5mV	0.057uA	943.5mV	0.087uA
54	938.9mV	0.037uA	937.6mV	0.064uA
55	936.7mV	0.081uA	938.6mV	0.088uA
56	941.5mV	0.055uA	942.0mV	0.077uA
57	941.4mV	0.051uA	942.3mV	0.042uA
58	936.2mV	0.088uA	943.4mV	0.045uA
59	938.2mV	0.060uA	938.9mV	0.039uA
60	940.5mV	0.097uA	934.7mV	0.078uA
61	934.4mV	0.079uA	935.9mV	0.057uA
62	939.1mV	0.082uA	943.9mV	0.056uA
63	942.8mV	0.041uA	934.7mV	0.087uA
64	936.8mV	0.059uA	936.0mV	0.033uA
65	936.2mV	0.089uA	937.2mV	0.061uA
66	941.3mV	0.065uA	935.7mV	0.038uA
67	942.6mV	0.047uA	936.5mV	0.097uA
68	943.1mV	0.056uA	941.1mV	0.070uA
69	935.8mV	0.062uA	942.5mV	0.093uA
70	939.7mV	0.074uA	937.3mV	0.033uA
71	941.7mV	0.051uA	938.6mV	0.090uA
72	936.0mV	0.080uA	935.3mV	0.094uA
73	941.4mV	0.081uA	934.8mV	0.089uA
74	937.9mV	0.056uA	938.0mV	0.081uA
75	940.7mV	0.067uA	938.9mV	0.089uA
76	935.7mV	0.034uA	936.6mV	0.062uA
77	941.5mV	0.091uA	937.8mV	0.083uA

Made By: Leo Hsia

Approval: Peter Yang



SeCoS Corporation

Temperature Cycle Test Data

Report No : T140820-001

Part No : DB1507S

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<1100mV@IF=1.5A, IR<10uA@VR=1000V

Test Condition: -55°C/30min, 150°C/30min, for1000 Cycle

Test Date: 2014.07.01 ~ 2014.08.20

Test Standard : JESD22 STANDER Method-A104

Operator: Leo Hsia

Test Result: PASS

No	Before		After	
	VF (mV)	IR (uA)	VF (mV)	IR (uA)
1	943.0mV	0.067uA	935.6mV	0.043uA
2	936.4mV	0.039uA	936.2mV	0.037uA
3	941.8mV	0.048uA	940.5mV	0.057uA
4	939.3mV	0.081uA	942.0mV	0.053uA
5	943.9mV	0.091uA	940.9mV	0.088uA
6	938.6mV	0.095uA	944.0mV	0.057uA
7	939.1mV	0.038uA	942.2mV	0.091uA
8	942.5mV	0.098uA	938.7mV	0.040uA
9	939.4mV	0.037uA	936.3mV	0.070uA
10	936.7mV	0.061uA	937.1mV	0.064uA
11	934.9mV	0.069uA	943.3mV	0.084uA
12	941.6mV	0.092uA	942.1mV	0.056uA
13	938.6mV	0.059uA	937.5mV	0.075uA
14	940.0mV	0.086uA	937.1mV	0.046uA
15	938.9mV	0.041uA	943.4mV	0.093uA
16	940.7mV	0.072uA	934.3mV	0.069uA
17	943.3mV	0.030uA	937.4mV	0.051uA
18	942.8mV	0.075uA	938.9mV	0.071uA
19	943.5mV	0.069uA	938.9mV	0.058uA
20	935.1mV	0.077uA	939.0mV	0.061uA
21	936.1mV	0.090uA	934.8mV	0.048uA
22	942.2mV	0.071uA	936.3mV	0.099uA
23	936.1mV	0.049uA	938.5mV	0.036uA
24	937.6mV	0.052uA	940.8mV	0.096uA
25	936.3mV	0.093uA	942.4mV	0.095uA
26	942.1mV	0.060uA	938.3mV	0.087uA
27	939.0mV	0.098uA	938.1mV	0.053uA
28	938.5mV	0.098uA	941.4mV	0.060uA
29	934.9mV	0.034uA	937.9mV	0.079uA
30	938.3mV	0.071uA	941.5mV	0.091uA
31	942.0mV	0.074uA	944.0mV	0.037uA
32	935.2mV	0.043uA	941.5mV	0.058uA
33	942.1mV	0.091uA	938.8mV	0.074uA
34	939.2mV	0.093uA	936.5mV	0.030uA
35	937.1mV	0.071uA	941.6mV	0.057uA
36	936.9mV	0.030uA	941.7mV	0.094uA
37	938.5mV	0.085uA	934.5mV	0.081uA
38	937.5mV	0.096uA	935.7mV	0.089uA
39	934.9mV	0.097uA	942.0mV	0.066uA
40	938.0mV	0.093uA	936.6mV	0.076uA



SeCoS Corporation

Temperature Cycle Test Data

Report No : T140820-001

Part No : DB1507S

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<1100mV@IF=1.5A, IR<10uA@VR=1000V

Test Condition: -55°C/30min, 150°C/30min, for1000 Cycle

Test Date: 2014.07.01 ~ 2014.08.20

Test Standard : JESD22 STANDER Method-A104

Operator: Leo Hsia

Test Result: PASS

No	Before		After	
	VF (mV)	IR (uA)	VF (mV)	IR (uA)
41	941.9mV	0.040uA	934.4mV	0.067uA
42	941.8mV	0.047uA	942.4mV	0.094uA
43	942.9mV	0.032uA	938.3mV	0.095uA
44	934.3mV	0.038uA	934.4mV	0.098uA
45	944.1mV	0.094uA	934.9mV	0.096uA
46	940.0mV	0.037uA	942.5mV	0.096uA
47	940.5mV	0.094uA	934.8mV	0.047uA
48	943.0mV	0.055uA	937.7mV	0.086uA
49	935.1mV	0.063uA	936.6mV	0.047uA
50	935.0mV	0.044uA	940.5mV	0.038uA
51	940.1mV	0.069uA	936.1mV	0.064uA
52	939.8mV	0.083uA	942.9mV	0.047uA
53	942.5mV	0.087uA	938.1mV	0.064uA
54	943.4mV	0.056uA	938.6mV	0.034uA
55	939.7mV	0.093uA	938.7mV	0.077uA
56	941.4mV	0.032uA	943.8mV	0.078uA
57	940.0mV	0.092uA	939.3mV	0.035uA
58	938.1mV	0.071uA	940.2mV	0.090uA
59	940.4mV	0.069uA	940.2mV	0.093uA
60	942.5mV	0.057uA	943.2mV	0.079uA
61	942.8mV	0.075uA	939.9mV	0.050uA
62	934.7mV	0.085uA	941.0mV	0.073uA
63	939.6mV	0.037uA	937.6mV	0.054uA
64	942.5mV	0.093uA	943.3mV	0.074uA
65	941.7mV	0.069uA	934.5mV	0.074uA
66	943.5mV	0.084uA	943.0mV	0.047uA
67	936.5mV	0.061uA	940.3mV	0.094uA
68	942.0mV	0.049uA	935.0mV	0.050uA
69	940.3mV	0.076uA	942.6mV	0.061uA
70	940.6mV	0.080uA	942.7mV	0.089uA
71	940.0mV	0.085uA	940.4mV	0.051uA
72	942.0mV	0.086uA	934.2mV	0.032uA
73	936.6mV	0.069uA	938.4mV	0.058uA
74	940.6mV	0.074uA	936.7mV	0.061uA
75	944.1mV	0.057uA	934.5mV	0.083uA
76	939.2mV	0.096uA	935.4mV	0.053uA
77	941.6mV	0.066uA	937.4mV	0.082uA



High Temperature High Humidity Test Data

Report No : T140820-001

Part No : DB1507S

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<1100mV@IF=1.5A, IR<10uA@VR=1000V

Test Condition: 85±2°C , 85±5%RH, 1000Hrs

Test Date: 2014.07.01 ~ 2014.08.13

Test Standard : JESD22 STANDER Method-A101

Operator: Leo Hsia

Test Result: PASS

No	Before		After	
	VF (mV)	IR (uA)	VF (mV)	IR (uA)
1	938.5mV	0.099uA	937.7mV	0.089uA
2	934.9mV	0.073uA	936.4mV	0.059uA
3	940.1mV	0.065uA	937.6mV	0.088uA
4	940.6mV	0.082uA	938.9mV	0.086uA
5	941.2mV	0.048uA	942.1mV	0.063uA
6	942.8mV	0.083uA	936.9mV	0.055uA
7	941.7mV	0.033uA	937.3mV	0.072uA
8	937.9mV	0.060uA	942.3mV	0.074uA
9	943.9mV	0.044uA	939.1mV	0.053uA
10	938.3mV	0.030uA	938.1mV	0.045uA
11	942.7mV	0.062uA	940.9mV	0.091uA
12	940.4mV	0.076uA	937.4mV	0.042uA
13	944.1mV	0.041uA	936.0mV	0.072uA
14	936.4mV	0.090uA	936.8mV	0.082uA
15	939.4mV	0.032uA	942.3mV	0.076uA
16	942.5mV	0.081uA	937.0mV	0.047uA
17	936.9mV	0.061uA	939.9mV	0.068uA
18	943.4mV	0.070uA	936.3mV	0.059uA
19	941.8mV	0.098uA	938.8mV	0.098uA
20	941.7mV	0.058uA	942.1mV	0.061uA
21	938.8mV	0.082uA	942.8mV	0.037uA
22	938.7mV	0.074uA	943.2mV	0.077uA
23	938.1mV	0.051uA	940.5mV	0.034uA
24	934.9mV	0.080uA	937.0mV	0.049uA
25	939.3mV	0.087uA	943.2mV	0.059uA
26	940.0mV	0.083uA	940.6mV	0.081uA
27	938.6mV	0.047uA	936.2mV	0.033uA
28	943.3mV	0.087uA	941.9mV	0.036uA
29	934.4mV	0.031uA	943.7mV	0.073uA
30	940.7mV	0.054uA	940.2mV	0.057uA
31	943.5mV	0.037uA	939.9mV	0.065uA
32	939.8mV	0.094uA	938.5mV	0.057uA
33	943.1mV	0.036uA	940.0mV	0.073uA
34	934.2mV	0.065uA	936.6mV	0.031uA
35	935.5mV	0.044uA	937.3mV	0.079uA
36	941.0mV	0.046uA	937.0mV	0.042uA
37	941.7mV	0.070uA	940.5mV	0.034uA
38	937.7mV	0.046uA	943.2mV	0.037uA
39	938.6mV	0.062uA	942.7mV	0.068uA
40	937.7mV	0.037uA	944.0mV	0.039uA



High Temperature High Humidity Test Data

Report No : T140820-001

Part No : DB1507S

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<1100mV@IF=1.5A, IR<10uA@VR=1000V

Test Condition: 85±2°C , 85±5%RH, 1000Hrs

Test Date: 2014.07.01 ~ 2014.08.13

Test Standard : JESD22 STANDER Method-A101

Operator: Leo Hsia

Test Result: PASS

No	Before		After	
	VF (mV)	IR (uA)	VF (mV)	IR (uA)
41	940.2mV	0.090uA	935.3mV	0.033uA
42	940.7mV	0.092uA	935.3mV	0.092uA
43	935.4mV	0.068uA	934.6mV	0.055uA
44	943.7mV	0.047uA	934.9mV	0.080uA
45	941.1mV	0.076uA	937.5mV	0.066uA
46	943.4mV	0.057uA	937.2mV	0.069uA
47	942.2mV	0.090uA	936.6mV	0.089uA
48	944.0mV	0.080uA	939.1mV	0.036uA
49	942.3mV	0.086uA	934.8mV	0.097uA
50	940.0mV	0.078uA	941.5mV	0.045uA
51	939.8mV	0.064uA	938.6mV	0.080uA
52	940.4mV	0.045uA	937.7mV	0.091uA
53	937.3mV	0.055uA	940.0mV	0.075uA
54	942.3mV	0.055uA	938.8mV	0.043uA
55	936.6mV	0.096uA	942.8mV	0.072uA
56	941.5mV	0.044uA	942.5mV	0.063uA
57	935.8mV	0.057uA	941.4mV	0.059uA
58	937.4mV	0.044uA	934.6mV	0.037uA
59	937.7mV	0.043uA	944.0mV	0.066uA
60	935.4mV	0.071uA	942.6mV	0.084uA
61	936.2mV	0.044uA	943.4mV	0.084uA
62	942.0mV	0.097uA	944.1mV	0.038uA
63	936.3mV	0.093uA	937.7mV	0.048uA
64	942.1mV	0.054uA	934.9mV	0.061uA
65	940.0mV	0.084uA	941.2mV	0.070uA
66	941.1mV	0.067uA	938.1mV	0.037uA
67	937.0mV	0.097uA	937.5mV	0.076uA
68	942.0mV	0.034uA	940.8mV	0.047uA
69	940.4mV	0.055uA	942.9mV	0.053uA
70	942.7mV	0.040uA	935.9mV	0.039uA
71	938.3mV	0.082uA	941.5mV	0.044uA
72	938.6mV	0.079uA	943.7mV	0.049uA
73	938.4mV	0.059uA	939.7mV	0.090uA
74	935.0mV	0.051uA	935.6mV	0.048uA
75	934.3mV	0.037uA	935.4mV	0.051uA
76	942.2mV	0.093uA	936.4mV	0.039uA
77	936.5mV	0.055uA	934.8mV	0.077uA



SeCoS Corporation

Solderability Test Data

Report No : T140820-001

Part No : DB1507S

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<1100mV@IF=1.5A, IR<10uA@VR=1000V

Test Condition: 245°C ± 5°C, 5Sec

Test Date: 2014.08.20 ~ 2014.08.20

Test Standard : JESD22 STANDER Method-B102

Operator: Leo Hsia

Test Result: PASS

No	Before		After	
	VF (mV)	IR (uA)	VF (mV)	IR (uA)
1	944.0mV	0.058uA	942.6mV	0.046uA
2	937.8mV	0.057uA	936.1mV	0.093uA
3	943.7mV	0.049uA	941.8mV	0.088uA
4	935.8mV	0.053uA	941.0mV	0.053uA
5	943.7mV	0.062uA	934.8mV	0.083uA
6	937.6mV	0.035uA	940.0mV	0.089uA
7	942.2mV	0.034uA	941.9mV	0.099uA
8	941.6mV	0.078uA	934.4mV	0.084uA
9	938.4mV	0.044uA	935.4mV	0.096uA
10	940.4mV	0.096uA	942.4mV	0.047uA

Made By: Leo Hsia

Approval: Peter Yang